## μΑ78L00 SERIES POSITIVE-VOLTAGE REGULATORS

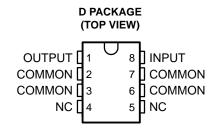
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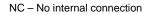
- 3-Terminal Regulators
- Output Current up to 100 mA
- No External Components
- Internal Thermal-Overload Protection
- Internal Short-Circuit Current Limiting
- Direct Replacements for Fairchild μA78L00 Series

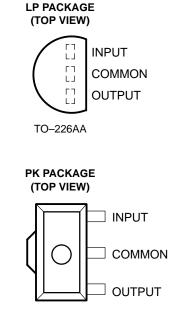
### description

This series of fixed-voltage integrated-circuit voltage regulators is designed for a wide range of applications. These applications include on-card regulation for elimination of noise and distribution problems associated with single-point regulation. In addition, they can be used with power-pass elements to make high-current voltage regulators. One of these regulators can deliver up to 100 mA of output current. The internal limiting and thermal-shutdown features of these regulators essentially make them immune to overload. When used as a replacement for a zener diode-resistor combination, an effective improvement in output impedance can be obtained, together with lower bias current.

The  $\mu$ A78L00C and  $\mu$ A78L00AC series are characterized for operation over the virtual junction temperature range of 0°C to 125°C. The  $\mu$ A78L05AI is characterized for operation over the virtual junction temperature range of -40°C to 125°C.







The center lead is in electrical contact with the tab.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



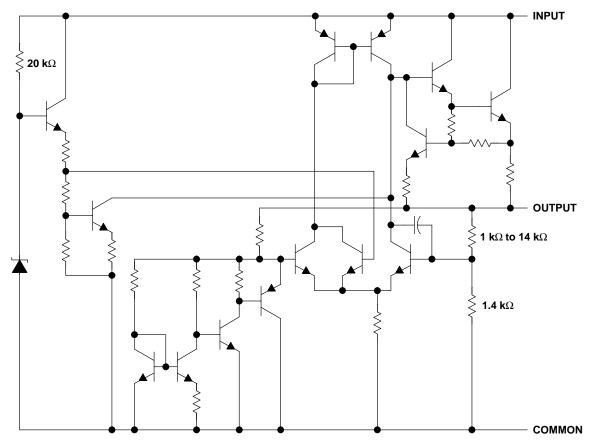
## $\mu\text{A78L00}$ SERIES POSITIVE-VOLTAGE REGULATORS

SLVS010P - JANUARY 1976 - REVISED JUNE 2002

			AV	AILABLE OPTION	IS						
				PACI	KAGE						
		SMALL O (D)	-	PLASTIC CYI (LP	-	SOT-89 (PK)					
	(V)		OUTPUT VOLTAGE TOLERANCE								
		5%	10%	5%	10%	5%	10%				
0°C to 125°C	2.6 5 6.2 8 9 10 12 15	μΑ78L02ACD μΑ78L05ACD – μΑ78L08ACD μΑ78L09ACD μΑ78L10ACD μΑ78L12ACD μΑ78L12ACD	_ μA78L05CD _ μA78L08CD _ _ _ _ _ _	μA78L02ACLP μA78L05ACLP μA78L06ACLP μA78L08ACLP μA78L09ACLP μA78L10ACLP μA78L12ACLP μA78L15ACLP	_ μA78L05CLP _ μA78L09CLP _ _ _ _	– µA78L05ACPK µA78L06ACPK µA78L08ACPK µA78L09ACPK µA78L10ACPK µA78L12ACPK µA78L15ACPK	_ μA78L05CPK _ μA78L08CPK _ _ _ _ _ _				
-40°C to 125°C	5	_	_	μA78L05AILP	_	_	_				

D and LP packages are available taped and reeled. Add the suffix R to the device type (e.g., µA78L05ACDR). The PK package is only available taped and reeled (do not add the suffix R to the device type).

### schematic



NOTE A: Resistor values shown are nominal.



## $\mu \text{A78L00 SERIES} \\ \text{POSITIVE-VOLTAGE REGULATORS} \\$

SLVS010P - JANUARY 1976 - REVISED JUNE 2002

#### absolute maximum ratings over virtual junction temperature range (unless otherwise noted)<sup>†</sup>

Input voltage, V <sub>I</sub> : μΑ78L02AC, μΑ78L05C–μΑ78L09C, μΑ78L10AC μΑ78L12C, μΑ78L12AC, μΑ78L15C, μΑ78L15AC	
Package thermal impedance, $\theta_{IA}$ (see Notes 1 and 2): D package	
Virtual junction temperature, T <sub>J</sub>	
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	
Storage temperature range, T <sub>stg</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. Maximum power dissipation is a function of T<sub>J</sub>(max), θ<sub>J</sub>A, and T<sub>A</sub>. The maximum allowable power dissipation at any allowable ambient temperature is P<sub>D</sub> = (T<sub>J</sub>(max) – T<sub>A</sub>)/θ<sub>J</sub>A. Operating at the absolute maximum T<sub>J</sub> of 150°C can affect reliability. Due to variations in individual device electrical characteristics and thermal resistance, the built-in thermal-overload protection may be activated at power levels slightly above or below the rated dissipation.

2. The package thermal impedance is calculated in accordance with JESD 51-7.

#### recommended operating conditions

			MIN	MAX	UNIT
		μA78L02AC	4.75	20	
Vj Input voltage	μΑ78L05C, μΑ78L05AC	7	20		
		μΑ78L06C, μΑ78L06AC	8.5	20	
	μΑ78L08C, μΑ78L08AC	10.5	23	v	
		μΑ78L09C, μΑ78L09AC	11.5	24	v
		μΑ78L10AC	12.5	25	
		μΑ78L12C, μΑ78L12AC	14.5	27	
		μΑ78L15C, μΑ78L15AC	17.5	30	
IO	IO Output current				mA
т.	Operating virtual junction temperature range	$\mu$ A78LxxC and $\mu$ A78LxxAC series	0	125	°C
Тј	Operating virtual junction temperature range	μA78L05AI	-40	125	Ŭ



## μA78L00 SERIES POSITIVE-VOLTAGE REGULATORS

SLVS010P - JANUARY 1976 - REVISED JUNE 2002

## electrical characteristics at specified virtual junction temperature, $V_I = 9 V$ , $I_O = 40 mA$ (unless otherwise noted)

	TEST CONDITIONS	- +	μ <b>Α78L02AC</b>			
PARAMETER	TEST CONDITIONS	т <sub>J</sub> †	MIN	TYP	MAX	UNIT
		25°C	2.5	2.6	2.7	
Output voltage	$V_{I} = 4.75$ V to 20 V, $I_{O} = 1$ mA to 40 mA	0°C to 125°C	2.45		2.75	V
	I <sub>O</sub> = 1 mA to 70 mA	0°C to 125°C	2.45		2.75	
Input voltage regulation	VI = 4.75 V to 20 V	25°C		20	100	mV
	$V_{I} = 5 V \text{ to } 20 V$	25°C		16	75	mv
Ripple rejection	$V_{I} = 6 V \text{ to } 20 V, \qquad f = 120 \text{ Hz}$	25°C	43	51		dB
	$I_{O} = 1 \text{ mA to } 100 \text{ mA}$	25°C		12	50	mV
Output voltage regulation	$I_{O} = 1 \text{ mA to } 40 \text{ mA}$	25 C		6	25	mv
Output noise voltage	f = 10 Hz to 100 kHz	25°C		30		μV
Dropout voltage		25°C		1.7		V
Diag ourrest		25°C		3.6	6	~ ^
Bias current		125°C			5.5	mA
Pice ourrent change	$V_{I} = 5 V \text{ to } 20 V$	0°C to 125°C			2.5	mA
Bias current change	$I_{O} = 1 \text{ mA to } 40 \text{ mA}$	0 0 1250			0.1	ШA

<sup>†</sup> Pulse-testing techniques maintain T<sub>J</sub> as close to T<sub>A</sub> as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-μF capacitor across the input and a 0.1-μF capacitor across the output.

electrical characteristics at specified virtual junction temperature, V <sub>I</sub> = 10 V, I <sub>O</sub> = 40 mA (unless	
otherwise noted)	

PARAMETER	TEST CONDITIONS	‡ <sub>ل</sub> T	μ <b>Α78L05C</b>			μ <b>Α78L05AC</b> μ <b>Α78L05AI</b>			UNIT
		-	MIN	TYP	MAX	MIN	TYP	MAX	
		25°C	4.6	5	5.4	4.8	5	5.2	
Output voltage	$V_{I} = 7 V \text{ to } 20 V$ , $I_{O} = 1 \text{ mA to } 40 \text{ mA}$	Full range	4.5		5.5	4.75		5.25	V
	I <sub>O</sub> = 1 mA to 70 mA	Full range	4.5		5.5	4.75		5.25	
Input	V <sub>I</sub> = 7 V to 20 V	25°C		32	200		32	150	mV
voltage regulation	V <sub>I</sub> = 8 V to 20 V	25-0		26	150		26	100	mv
Ripple rejection	V <sub>I</sub> = 8 V to 18 V, f = 120 Hz	25°C	40	49		41	49		dB
Output	I <sub>O</sub> = 1 mA to 100 mA	25°C		15	60		15	60	mV
voltage regulation	$I_{O} = 1 \text{ mA to } 40 \text{ mA}$	25°C		8	30		8	30	mv
Output noise voltage	f = 10 Hz to 100 kHz	25°C		42			42		μV
Dropout voltage		25°C		1.7			1.7		V
Bias current		25°C		3.8	6		3.8	6	mA
Bias current		125°C			5.5			5.5	mA
Bias	V <sub>I</sub> = 8 V to 20 V				1.5			1.5	mA
current change	$I_{O} = 1 \text{ mA to } 40 \text{ mA}$	Full range			0.2			0.1	IIIA

<sup>‡</sup> Pulse-testing techniques maintain T<sub>J</sub> as close to T<sub>A</sub> as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33- $\mu$ F capacitor across the input and a 0.1- $\mu$ F capacitor across the output. Full range for the  $\mu$ A78L05AC is T<sub>J</sub> = 0°C to 125°C and full range for the  $\mu$ A78L05AI is T<sub>J</sub> = -40°C to 125°C.



# $\mu \text{A78L00 SERIES} \\ \text{POSITIVE-VOLTAGE REGULATORS} \\$

SLVS010P - JANUARY 1976 - REVISED JUNE 2002

electrical characteristics at specified virtual junction temperature, $V_I$ = 12 V, $I_O$ = 40 mA (unle	SS
otherwise noted)	

PARAMETER	TEST CONDITIONS	τ <sub>J</sub> †	μ <b>Α78L06C</b>			μ <b>Α</b>	UNIT			
PARAMETER			MIN	TYP	MAX	MIN	TYP	MAX	UNIT	
		25°C	5.7	6.2	6.7	5.95	6.2	6.45		
Output voltage	$V_{I} = 8.5 V \text{ to } 20 V$ , $I_{O} = 1 \text{ mA to } 40 \text{ mA}$	0°C to 125°C	5.6		6.8	5.9		6.5	V	
	I <sub>O</sub> = 1 mA to 70 mA	0°C to 125°C	5.6		6.8	5.9		6.5		
Input	VI = 8.5 V to 20 V	2500		35	200		35	175	mV	
voltage regulation	VI = 9 V to 20 V	25°C		29	150		29	125	mv	
Ripple rejection	V <sub>I</sub> = 10 V to 20 V, f = 120 Hz	25°C	39	48		40	48		dB	
Output	I <sub>O</sub> = 1 mA to 100 mA	25°C		16	80		16	80		
voltage regulation	$I_{O} = 1 \text{ mA to } 40 \text{ mA}$	250		9	40		9	40	mV	
Output noise voltage	f = 10 Hz to 100 kHz	25°C		46			46		μV	
Dropout voltage		25°C		1.7			1.7		V	
Diag ourrent		25°C		3.9	6		3.9	6	~^^	
Bias current		125°C			5.5			5.5	mA	
Bias	$V_{I} = 9 V$ to 20 V	0°C to 125°C			1.5			1.5	~^^	
current change	$I_{O} = 1 \text{ mA to } 40 \text{ mA}$	0°C to 125°C			0.2			0.1	mA	

<sup>†</sup> Pulse-testing techniques maintain T<sub>J</sub> as close to T<sub>A</sub> as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-μF capacitor across the input and a 0.1-μF capacitor across the output.

electrical characteristics at specified virtual junction temperature, V <sub>I</sub> = 14 V, I <sub>O</sub> = 40 mA (unless	
otherwise noted)	

PARAMETER	TEST CONDITIONS	T.T	μ <b>Α78L08C</b>			μΑ	UNIT			
PARAMETER	TEST CONDITIONS	T <sub>J</sub> †	MIN	TYP	MAX	MIN	TYP	MAX		
		25°C	7.36	8	8.64	7.7	8	8.3		
Output voltage	$V_{I} = 10.5 V \text{ to } 23 V$ , $I_{O} = 1 \text{ mA to } 40 \text{ mA}$	0°C to 125°C	7.2		8.8	7.6		8.4	V	
	I <sub>O</sub> = 1 mA to 70 mA	0°C to 125°C	7.2		8.8	7.6		8.4		
Input voltage	V <sub>I</sub> = 10.5 V to 23 V	25°C		42	200		42	175	mV	
regulation	V <sub>I</sub> = 11 V to 23 V	25 C		36	150		36	125	IIIV	
Ripple rejection	V <sub>I</sub> = 13 V to 23 V, f = 120 Hz	25°C	36	46		37	46		dB	
Output voltage	I <sub>O</sub> = 1 mA to 100 mA	25°C		18	80		18	80	mV	
regulation	$I_{O} = 1 \text{ mA to } 40 \text{ mA}$	25 C		10	40		10	40		
Output noise voltage	f = 10 Hz to 100 kHz	25°C		54			54		μV	
Dropout voltage		25°C		1.7			1.7		V	
Diag ourrent		25°C		4	6		4	6	~^^	
Bias current		125°C			5.5			5.5	mA	
Bias	$V_{I} = 5 V \text{ to } 20 V$	0°C to 125°C			1.5			1.5	<b>m</b> A	
current change	$I_{O} = 1 \text{ mA to } 40 \text{ mA}$	0°C to 125°C			0.2			0.1	mA	

<sup>†</sup> Pulse-testing techniques maintain T<sub>J</sub> as close to T<sub>A</sub> as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-μF capacitor across the input and a 0.1-μF capacitor across the output.



## μΑ78L00 SERIES POSITIVE-VOLTAGE REGULATORS

SLVS010P - JANUARY 1976 - REVISED JUNE 2002

## electrical characteristics at specified virtual junction temperature, $V_I = 16$ V, $I_O = 40$ mA (unless otherwise noted)

DADAMETED	TEST CONDITIONS	т <sub>J</sub> †	μ <b>Α78L09C</b>			μΑ	UNIT		
PARAMETER			MIN	TYP	MAX	MIN	TYP	MAX	UNIT
		25°C	8.3	9	9.7	8.6	9	9.4	
Output voltage	$V_{I} = 12 V \text{ to } 24 V$ , $I_{O} = 1 \text{ mA to } 40 \text{ mA}$	0°C to 125°C	8.1		9.9	8.55	-	9.45	V
	I <sub>O</sub> = 1 mA to 70 mA	0°C to 125°C	8.1		9.9	8.55		9.45	
Input	V <sub>I</sub> = 12 V to 24 V	25°C		45	225		45	175	
voltage regulation	V <sub>I</sub> = 13 V to 24 V	25%		40	175		40	125	mV
Ripple rejection	V <sub>I</sub> = 15 V to 25 V, f = 120 Hz	25°C	36	45		38	45		dB
Output	I <sub>O</sub> = 1 mA to 100 mA	25°C		19	90		19	90	mV
voltage regulation	I <sub>O</sub> = 1 mA to 40 mA	25 C		11	40		11	40	
Output noise voltage	f = 10 Hz to 100 kHz	25°C		58			58		μV
Dropout voltage		25°C		1.7			1.7		V
Diag ourreat		25°C		4.1	6		4.1	6	mA
Bias current		125°C			5.5			5.5	mA
Bias	VI = 13 V to 24 V	0°C to 125°C			1.5			1.5	
current change	$I_{O} = 1 \text{ mA to } 40 \text{ mA}$	0°C to 125°C			0.2			0.1	mA

<sup>†</sup> Pulse-testing techniques maintain T<sub>J</sub> as close to T<sub>A</sub> as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-μF capacitor across the input and a 0.1-μF capacitor across the output.

electrical characteristics at specified virtual junction temperature, V <sub>I</sub> = 14 V, I <sub>O</sub> = 40 mA (unless	
otherwise noted)	

PARAMETER	TEET	CONDITIONS	- +	μ <b>Α7</b> 8		A78L10AC		
PARAMETER	1251 0	CONDITIONS	TJ‡	MIN	TYP	MAX	UNIT	
Output voltage			25°C	9.6	10	10.4		
	V <sub>I</sub> = 13 V to 25 V,	$I_{O} = 1 \text{ mA to } 40 \text{ mA}$	0°C to 125°C	9.5		10.5	V	
	I <sub>O</sub> = 1 mA to 70 mA		0°C to 125°C	9.5		10.5		
	V <sub>I</sub> = 13 V to 25 V		25°C		51	175	mV	
Input voltage regulation	V <sub>I</sub> = 14 V to 25 V		25-0		42	125		
Ripple rejection	$V_{I} = 15 V \text{ to } 25 V,$	f = 120 Hz	25°C	37	44		dB	
Output voltage regulation	$I_{O} = 1 \text{ mA to } 100 \text{ mA}$		25°C		20	90	mV	
	$I_{O} = 1 \text{ mA to } 40 \text{ mA}$		25 C		11	40		
Output noise voltage	f = 10 Hz to 100 kHz		25°C		62		μV	
Dropout voltage			25°C		1.7		V	
Bias current			25°C		4.2			
Blas current			125°C			5.5	mA	
Bias current change	VI = 14 V to 25 V		0°C to 125°C			1.5	~^^	
Blas current change	$I_{O} = 1 \text{ mA to } 40 \text{ mA}$		0°C to 125°C			0.1	mA	

<sup>†</sup> Pulse-testing techniques maintain T<sub>J</sub> as close to T<sub>A</sub> as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-μF capacitor across the input and a 0.1-μF capacitor across the output.



# $\mu \text{A78L00 SERIES} \\ \text{POSITIVE-VOLTAGE REGULATORS} \\$

SLVS010P - JANUARY 1976 - REVISED JUNE 2002

electrical characteristics at specified virtual junction temperature, V <sub>I</sub> = 19 V, I <sub>O</sub> = 40 mA (unless	5
otherwise noted)	

PARAMETER	TEST CONDITIONS	TJ‡	μ <b>Α78L12C</b>			μ <b>Α78L12AC</b>			
	TEST CONDITIONS		MIN	TYP	MAX	MIN	TYP	MAX	UNIT
Output voltage		25°C	11.1	12	12.9	11.5	12	12.5	V
	$V_{I} = 14 V \text{ to } 27 V$ , $I_{O} = 1 \text{ mA to } 40 \text{ mA}$	0°C to 125°C	10.8		13.2	11.4		12.6	
	I <sub>O</sub> = 1 mA to 70 mA	0°C to 125°C	10.8		13.2	11.4		12.6	
Input	V <sub>I</sub> = 14.5 V to 27 V	25°C		55	250		55	250	mV
voltage regulation	V <sub>I</sub> = 16 V to 27 V	250		49	200		49	200	
Ripple rejection	V <sub>I</sub> = 15 V to 25 V, f = 120 Hz	25°C	36	42		37	42		dB
Output voltage regulation	I <sub>O</sub> = 1 mA to 100 mA	25°C		22	100		22	100	mV
	$I_{O} = 1 \text{ mA to } 40 \text{ mA}$	250		13	50		13	50	
Output noise voltage	f = 10 Hz to 100 kHz	25°C		70			70		μV
Dropout voltage		25°C		1.7			1.7		V
Bias current		25°C		4.3	6.5		4.3	6.5	mA
		125°C			6			6	
Bias current change	V <sub>I</sub> = 16 V to 27 V	0°C to 125°C			1.5			1.5	~^^
	I <sub>O</sub> = 1 mA to 40 mA	0°C to 125°C			0.2			0.1	mA

<sup>†</sup> Pulse-testing techniques maintain T<sub>J</sub> as close to T<sub>A</sub> as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-μF capacitor across the input and a 0.1-μF capacitor across the output.

electrical characteristics at specified virtual junction temperature, VI = 23 V, IO = 40 mA (unless	
otherwise noted)	

PARAMETER	TEST CONDITIONS	т <sub>J</sub> †	μ <b>Α78L15C</b>			μ <b>Α78L15AC</b>			UNIT
	TEST CONDITIONS		MIN	TYP	MAX	MIN	TYP	MAX	UNIT
Output voltage	$V_{I} = 17.5 V \text{ to } 30 V$ , $I_{O} = 1 \text{ mA to } 40 \text{ mA}$	25°C	13.8	15	16.2	14.4	15	15.6	V
		0°C to 125°C	13.5		16.5	14.25		15.75	
	$I_{O} = 1 \text{ mA to } 70 \text{ mA}$	0°C to 125°C	13.5		16.5	14.25		15.75	
Input voltage regulation	VI = 17.5 V to 30 V			65	300		65	300	
	V <sub>I</sub> = 20 V to 30 V	25°C		58	250		58	250	mV
Ripple rejection	$V_I = 18.5 V$ to 28.5 V, f = 120 Hz	25°C	33	39		34	39		dB
Output	$I_{O} = 1 \text{ mA to } 100 \text{ mA}$	25°C		25	150		25	150	mV
voltage regulation	$I_{O} = 1 \text{ mA to } 40 \text{ mA}$	25'0		15	75		15	75	
Output noise voltage	f = 10 Hz to 100 kHz	25°C		82			82		μV
Dropout voltage		25°C		1.7			1.7		V
Bias current		25°C		4.6	6.5		4.6	6.5	mA
		125°C			6			6	
Bias	$V_I = 10 \text{ V} \text{ to } 30 \text{ V}$	0°C to 125°C			1.5			1.5	mA
current change	$I_{O} = 1 \text{ mA to } 40 \text{ mA}$	0 0 10 125 0			0.2			0.1	

<sup>†</sup> Pulse-testing techniques maintain T<sub>J</sub> as close to T<sub>A</sub> as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-μF capacitor across the input and a 0.1-μF capacitor across the output.



## $\mu\text{A78L00}$ SERIES POSITIVE-VOLTAGE REGULATORS

SLVS010P - JANUARY 1976 - REVISED JUNE 2002

### **APPLICATION INFORMATION**

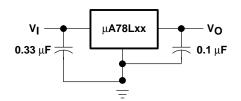


Figure 1. Fixed-Output Regulator

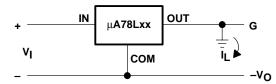


Figure 2. Positive Regulator in Negative Configuration (VI Must Float)

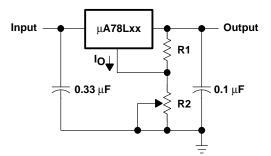
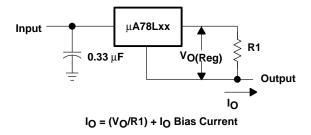


Figure 3. Adjustable-Output Regulator

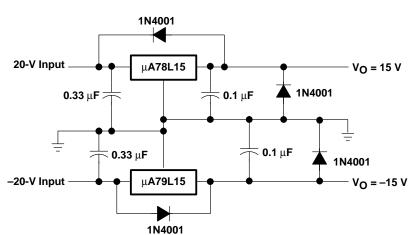






## μA78L00 SERIES POSITIVE-VOLTAGE REGULATORS

SLVS010P - JANUARY 1976 - REVISED JUNE 2002



### **APPLICATION INFORMATION**

Figure 5. Regulated Dual Supply

### operation with a load common to a voltage of opposite polarity

In many cases, a regulator powers a load that is not connected to ground, but instead, is connected to a voltage source of opposite polarity (e.g., operational amplifiers, level-shifting circuits, etc.). In these cases, a clamp diode should be connected to the regulator output as shown in Figure 6. This protects the regulator from output polarity reversals during startup and short-circuit operation.

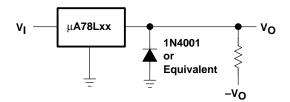


Figure 6. Output Polarity-Reversal-Protection Circuit

#### reverse-bias protection

Occasionally, the input voltage to the regulator can collapse faster than the output voltage. This can occur, for example, when the input supply is crowbarred during an output overvoltage condition. If the output voltage is greater than approximately 7 V, the emitter-base junction of the series-pass element (internal or external) could break down and be damaged. To prevent this, a diode shunt can be employed as shown in Figure 7.

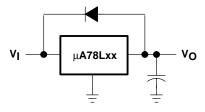


Figure 7. Reverse-Bias-Protection Circuit



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